

OBJECTIVE SPECIFICATIONS

Features

- Function, pin-out, speed and drive compatibility with 54/74ALS logic family
- Low power consumption characteristic of CMOS
- High-Drive-Current outputs:
 $I_{OL} = 8 \text{ mA} @ V_{OL} = 0.5V$
- Inputs and outputs interface directly with TTL, NMOS and CMOS devices
- Wide operating voltage range: 4.5V to 5.5V
- Characterized for operation over industrial and military temperature ranges:

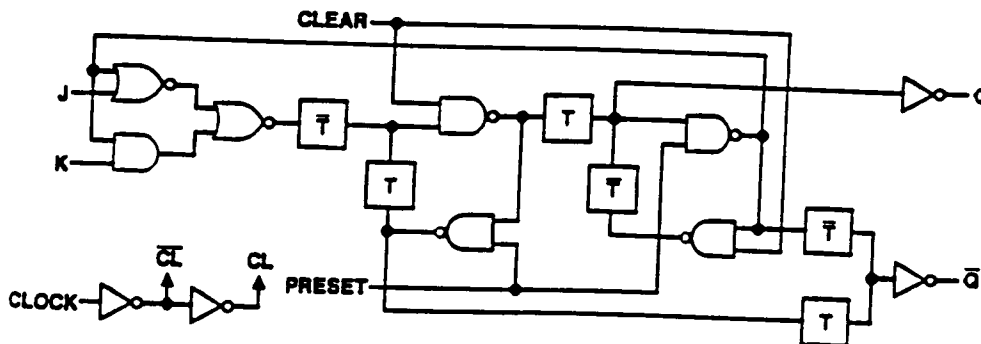
74AHCT: -40°C to $+85^{\circ}\text{C}$
54AHCT: -55°C to $+125^{\circ}\text{C}$

Function Table

Inputs		Inputs			Outputs	
$\overline{\text{PRE}}$	$\overline{\text{CLR}}$	CLK	J	K	Q	\overline{Q}
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H*	H*
H	H	↓	L	L	Q_n	Q_n
H	H	↓	H	L	H	L
H	H	↓	L	H	L	H
H	H	↓	H	H	TOGGLE	
H	H	H	X	X	Q_n	Q_n

*Both outputs will remain high as long as preset and clear are low, but the output states are unpredictable if preset and clear go high simultaneously.

Logic Diagrams



0020-2

Dual J-K Negative-Edge-Triggered Flip-Flops with Preset and Clear

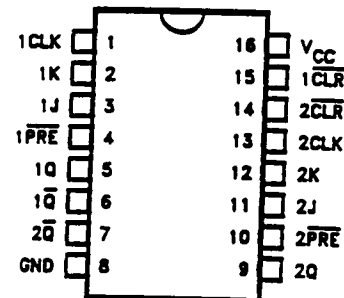
Description

These devices contain two negative-edge-triggered J-K flip-flops with independent J, K, preset, clear inputs and clocks and complementary outputs. The J-K inputs at each flip-flop are enabled when the clock goes high. The input data are transferred to the outputs on the negative-going edge of the clock pulse, provided the setup requirements have been met.

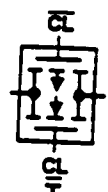
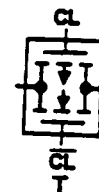
Fabrication using ISI proprietary ICE-MOS process, these devices provide speeds and drive capability equivalent to their ALSTTL counterparts and yet maintain CMOS power levels. The input and output voltage levels allow direct interface with TTL, NMOS and CMOS devices without any external components.

All inputs and outputs are protected from damage due to static discharge by internal diode clamps to V_{CC} and ground.

Pin Configuration



0020-1



0020-3

Absolute Maximum Ratings*

Supply Voltage Range, V_{CC} -0.5V to 7V
 DC Input Diode Current, I_{IK}
 ($V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$) ± 20 mA
 DC Output Diode Current, I_{OK}
 ($V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$) ± 20 mA
 Continuous Output Current Per Pin, I_O
 ($-0.5V < V_O < V_{CC} + 0.5V$) ± 35 mA
 Continuous Current Through
 V_{CC} or GND pins ± 125 mA
 Storage Temperature Range, T_{STG} .. -65°C to +150°C
 Power Dissipation Per Package, P_D † 500 mW

*Absolute Maximum Ratings are those values beyond which permanent damage to the device may occur. These are stress ratings only and functional operation of the device at or beyond them is not implied. Long exposure to these conditions may affect device reliability.

† Power Dissipation temperature derating:
 Plastic Package (N): -12 mW/°C from 65°C to 85°C
 Ceramic Package (J): -12 mW/°C from 100°C to 125°C

Recommended Operating Conditions

Supply Voltage, V_{CC} 4.5V to 5.5V
 DC Input & Output Voltages*, V_{IN} , V_{OUT} 0V to V_{CC}
 Operating Temperature
 Range
 74AHCT: -40°C to +85°C
 54AHCT: -55°C to +125°C
 Input Rise & Fall Times, t_r , t_f Max 500 ns

*Unused inputs must always be tied to an appropriate logic voltage level (either V_{CC} or GND)

DC Electrical Characteristics ($V_{CC} = 5V \pm 10\%$ Unless Otherwise Specified)

Symbol	Parameter	Test Conditions	$T_A = 25^\circ C$		74AHCT	54AHCT	Unit
			Typ	Guaranteed Limits			
				$T_A = -40^\circ C$ to $+85^\circ C$	$T_A = -55^\circ C$ to $+125^\circ C$		
V_{IH}	Minimum High-Level Input Voltage			2.0	2.0	2.0	V
V_{IL}	Maximum Low-Level Input Voltage			0.8	0.8	0.8	V
V_{OH}	Minimum High-Level Output Voltage	$V_{IN} = V_{IH}$ or V_{IL} $I_O = -20 \mu A$ $I_O = -4 mA$	V_{CC} 4.2	$V_{CC} - 0.1$ 3.98	$V_{CC} - 0.1$ 3.84	$V_{CC} - 0.1$ 3.7	V
V_{OL}	Maximum Low-Level Output Voltage	$V_{IN} = V_{IH}$ or V_{IL} $I_O = 20 \mu A$ $I_O = 4 mA$ $I_O = 8 mA$	0	0.1 0.26 0.39	0.1 0.33 0.5	0.1 0.4	V
I_{IN}	Maximum Input Current	$V_{IN} = V_{CC}$ or GND		± 0.1	± 1.0	± 1.0	μA
I_{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND $I_{OUT} = 0 \mu A$		4.0	40.0	80.0	μA

AC Electrical Characteristics (Input $t_r, t_f \leq 2$ ns), AHCT112

Symbol	Parameter		Conditions†	$T_A = 25^\circ\text{C}$	74AHCT	54AHCT	Unit
				$V_{CC} = 5.0\text{V}$	$T_A = -40^\circ\text{C to } +85^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$	
				Typ	Guaranteed Limits		
f_{max}	Maximum Clock Frequency		$C_L = 50$ pF	50	30	25	MHz
t_{PLH}	Maximum Propagation Delay, CLK to Q or \bar{Q}			10	17	20	ns
t_{PHL}				10	17	20	
t_{PLH}	Maximum Propagation Delay, PRE or \bar{CLR} to Q or \bar{Q}			10	17	20	ns
t_{PHL}				10	17	20	
t_{su}	Minimum Setup Time before CLK ↓	J or K		6	22	25	ns
		PRE or \bar{CLR} Inactive	6	20	22		
t_h	Minimum Hold Time, J or K after CLK ↓		0	0	0	ns	
t_w	Minimum Pulse Width	CLK High or Low	10	17	20	ns	
		PRE or \bar{CLR} Low	6	10	15		
C_{IN}	Maximum Input Capacitance		5			pF	
CPD	Power Dissipation Capacitance*		(per flip-flop)	40			pF

*CPD determines the no-load dynamic power dissipation: $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$.

†For AC switching test circuits and timing waveforms see section 2.